

VNQ500PEP-E

QUAD CHANNEL HIGH SIDE DRIVER

TARGET SPECIFICATION

Table 1. General Features

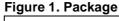
Туре	R _{DS(on)}	I _{OUT}	V _{CC}
VNQ500PEP-E	$500~\text{m}\Omega$	0.4 A	36V

- CMOS COMPATIBLE I/O's
- **■**CHIP ENABLE
- JUNCTION OVERTEMPERATURE PROTECTION AND DIAGNOSTIC
- **CURRENT LIMITATION**
- SHORTED LOAD PROTECTION
- UNDERVOLTAGE SHUTDOWN
- PROTECTION AGAINST LOSS OF GROUND
- VERY LOW STAND-BY CURRENT
- IN COMPLIANCE WITH THE 2002/95/EC **EUROPEAN DIRECTIVE**

DESCRIPTION

The VNQ500PEP-E is a monolithic device designed in STMicroelectronics VIPower M0-3 Technology, intended for driving any kind of load with one side connected to ground.

Active current limitation combined with latched thermal shutdown, protect the device against overload.





In case of overtemperature of one channel the relative I/O pin is pulled down.

Device automatically turns off in case of ground pin disconnection.

Table 2. Order Codes

Package	Tube	Tape and Reel
PowerSSO-12	VNQ500PEP-E	VNQ500PEPTR-E

Rev. 1

October 2004

Figure 2. Block Diagram

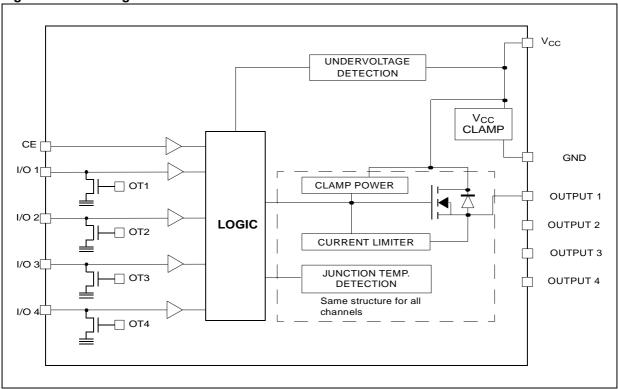


Table 3. Pin Definitions And Functions

Pin No	Symbol	Function			
TAB	V _{CC}	Positive power supply voltage			
7,12	V _{CC}	Positive power supply voltage			
1	GND	Logic ground			
2	CE	Chip Enable			
3	I/O 1	Input/Output of channel 1			
4	I/O 2	Input/Output of channel 2			
5	I/O 3	Input/Output of channel 3			
6	I/O 4	Input/Output of channel 4			
8	OUTPUT 4	High-Side output of channel 4			
9	OUTPUT 3	High-Side output of channel 3			
10	OUTPUT 2	High-Side output of channel 2			
11	OUTPUT 1	High-Side output of channel 1			

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Table 4. Absolute Maximum Ratings

Symbol	Parameter	Value	Unit
Vcc	DC Supply voltage	41	V
-V _{CC}	Reverse supply voltage	-0.3	V
- I _{GND}	DC Ground pin reverse current	- 250	mA
I _{OUT}	DC Output current	Internally Limited	Α
- I _{OUT}	Reverse DC output current	-1	Α
I _{IN}	DC Input current	+/- 10	mA
V _{ESD}	Electrostatic discharge (R=1.5KΩ; C=100pF) - I/On - OUTn & Vcc	4000 5000	V V
Tj	Junction operating temperature	Internally Limited	°C
T _{stg}	Storage temperature	- 55 to 150	°C

Figure 3. Configuration Diagram (Top View)

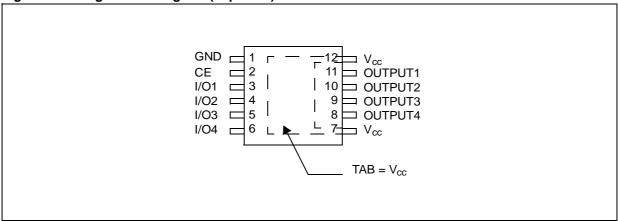
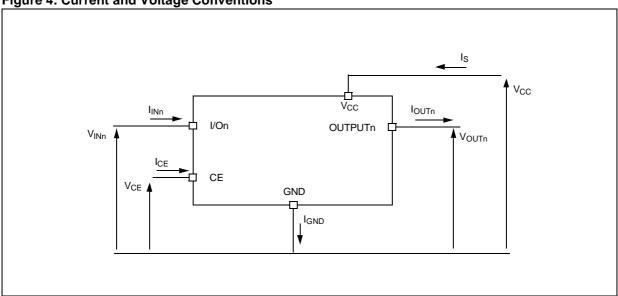


Figure 4. Current and Voltage Conventions



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Table 5. Thermal Data

Symbol	Parameter		Value	Unit
R _{thj-case}	Thermal Resistance Junction-case	Max	4.6	°C/W
R _{thj-amb}	Thermal Resistance Junction-ambient	Max	60 ^(*)	°C/W

Note: (*) When mounted on FR4 printed circuit board with 0.5 cm 2 of copper area (at least 35 μ thick) connected to all TAB pins.

$\textbf{ELECTRICAL CHARACTERISTICS} \ (8 \text{V} < \text{V}_{CC} < 36 \text{V}; \ -40 ^{\circ}\text{C} < \text{T}_{j} < 150 ^{\circ}\text{C} \ unless \ otherwise \ specified)$

Table 6. Power

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{CC} (**)	Operating supply voltage		5.5	13	36	V
V _{USD} (**)	Undervoltage shut-down		3	4	5.5	V
V _{OV} (**)	Overvoltage shutdown		36			V
R _{ON}	On state resistance	I _{OUTn} =0.25A; T _j =25°C I _{OUTn} =0.25A			500 1000	mΩ mΩ
I _S	Supply current	V _{CE} =V _{I/On} =0V; V _{CC} =13V; T _{case} =25°C On state (all channels ON); V _{CC} =13V			20 8	μA mA
I _{LGND} (**)	Output current at turn-off	$V_{CC}=V_{CE}=V_{I/On}=V_{GND}=13V$ $V_{OUT}=0V$			1	mA
I _{L(off)} (**)	Off state output current	V _{I/On} =V _{OUTn} =0V	0		5	μΑ
I _{Loff2} (**)	Off state output current	$V_{I/On}$ =0V, V_{OUTn} =0V, V_{CC} =13V; T_{case} =25°C			1	μА

Note: (**) Per channel

Table 7. Switching $(V_{CC} = 13V)$

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{on}	Turn-on time	R _L =52Ω from 80% V _{OUT} ⁽¹⁾		50		μs
t _{off}	Turn-off time	R _L =52Ω to 10% V _{OUT} ⁽¹⁾		75		μs
dV _{OUT} / dt _(on)	Turn-on voltage slope	R_L =52 Ω from V_{OUT} =1.3 V to V_{OUT} =10.4 V ⁽¹⁾		0.3		V/μs
dV _{OUT} / dt _(off)	Turn-off voltage slope	R_L =52 Ω from V_{OUT} =11.7 V to V_{OUT} =1.3 V (1)		0.3		V/μs

Note: (1) see figure 5 :switching time waveforms

Table 8. Input & CE Pin

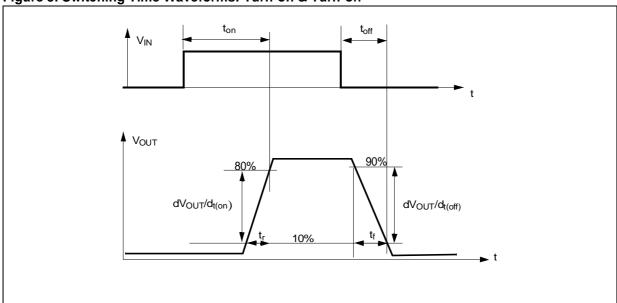
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{INL}	I/O low level				1.25	V
I _{INL}	Low level I/O current	V _{IN} =1.25V	1			μΑ
V _{INH}	I/O high level		3.25			V
I _{INH}	High level I/O current	V _{IN} =3.25V			10	μΑ
V _{I(hyst)}	I/O hysteresis voltage		0.5			V
V _{ICL}	Input Clamp Voltage	I _{IN} =1mA I _{IN} =-1mA	6	6.8 -0.7	8	V V

ELECTRICAL CHARACTERISTICS (continued)

Table 9. Protections

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{OL}	I/O low level default	I _{IN} =1mA, latched thermal shutdown			0.5	V
VOL	detection	IN-IIIA, latelled thermal shutdown			0.5	V
T _{TSD}	Junction shut-down		150	175	200	°C
1150	temperature		130	173	200	O
l _{lim}	DC Short circuit current	V_{CC} =13V; R_{LOAD} =10m Ω	0.4		0.9	Α
V.	Turn-off output clamp	I _{ОПТ} =0.25 A; L=50mH	V _{CC} -41	V _{CC} -48	V 55	V
V _{demag}	voltage	10UT=0.25 A, L=50111H	VCC-41	VCC-40	V _{CC} -55	V
t _{reset}	Thermal latch reset time	Tj < T _{TSD} (see figure 3 in waveforms)			10	μs

Figure 5. Switching Time Waveforms: Turn-on & Turn-off





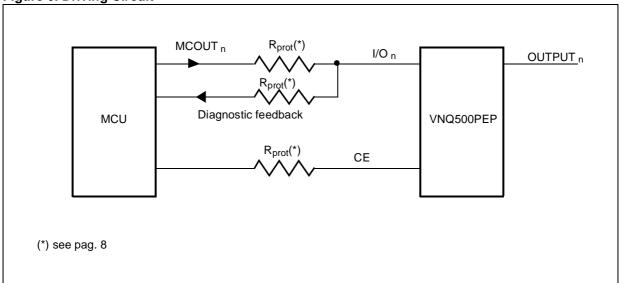


Figure 7. Truth Table

CONDITIONS	MCOUTn	CE	I/On	OUTPUTn
Normal operation	L H	H H	L H	I
Current limitation	L	H	L	L
	H	H	H	H
Overtemperature	L	H	L	L
	H	H	L (latched)	L
Undervoltage	L	H	L	L
	H	H	H	L
Stand-by	X	L	X	L

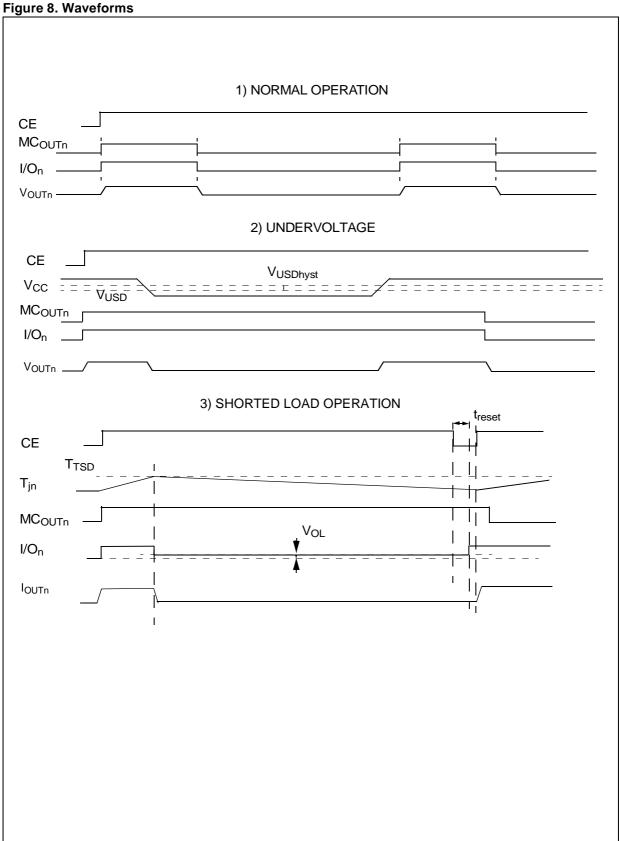
Table 10. Electrical Transient Requirements On $V_{\mbox{\footnotesize{CC}}}$ Pin

ISO T/R 7637/1	TEST LEVELS						
Test Pulse	I	II	III	IV	Delays and Impedance		
1	-25 V	-50 V	-75 V	-100 V	2 ms 10 Ω		
2	+25 V	+50 V	+75 V	+100 V	$0.2~\text{ms}~10~\Omega$		
3a	-25 V	-50 V	-100 V	-150 V	0.1 μs 50 Ω		
3b	+25 V	+50 V	+75 V	+100 V	0.1 μs 50 Ω		
4	-4 V	-5 V	-6 V	-7 V	100 ms, 0.01 Ω		
5	+26.5 V	+46.5 V	+66.5 V	+86.5 V	400 ms, 2 Ω		

ISO T/R 7637/1		TEST LEVEL	S RESULTS	
Test Pulse	l	II	≡	IV
1	С	С	С	С
2	С	С	С	С
3a	С	С	С	С
3b	С	С	С	С
4	С	С	С	С
5	С	E	E	E

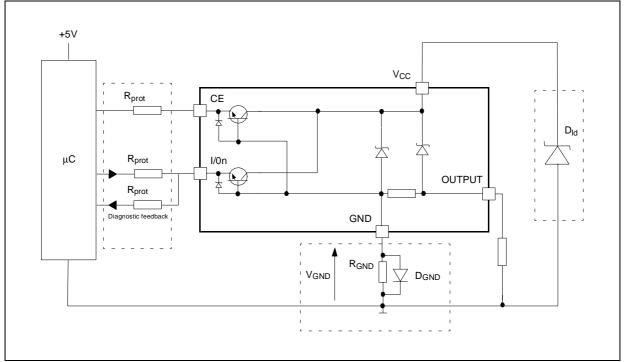
CLASS	CONTENTS
С	All functions of the device are performed as designed after exposure to disturbance.
E	One or more functions of the device is not performed as designed after exposure to disturbance and cannot be returned to proper operation without replacing the device.





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Figure 9. Application Schematic



GND PROTECTION NETWORK AGAINST REVERSE BATTERY

Solution 1: Resistor in the ground line (R_{GND} only). This can be used with any type of load.

The following is an indication on how to dimension the $R_{\mbox{\footnotesize{GND}}}$ resistor.

- 1) $R_{GND} \le 600 \text{mV} / (I_{S(on)max})$.
- 2) $R_{GND} \ge (-V_{CC}) / (-I_{GND})$

where $-I_{GND}$ is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device's datasheet.

Power Dissipation in R_{GND} (when V_{CC} <0: during reverse battery situations) is:

 $P_D = (-V_{CC})^2 / R_{GND}$

This resistor can be shared amongst several different HSD. Please note that the value of this resistor should be calculated with formula (1) where $I_{S(on)max}$ becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not common with the device ground then the R_{GND} will produce a shift ($I_{S(on)max} \ ^* R_{GND}$) in the input thresholds and the status output values. This shift will vary depending on many devices are ON in the case of several high side drivers sharing the same $R_{GND}.$

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then the ST suggests to utilize Solution 2 (see below).

Solution 2: A diode (DGND) in the ground line.

A resistor (R_{GND} =1k Ω) should be inserted in parallel to D_{GND} if the device will be driving an inductive load.

This small signal diode can be safely shared amongst several different HSD. Also in this case, the presence of the ground network will produce a shift (≃600mV) in the input threshold and the status output values if the microprocessor ground is not common with the device ground. This shift will not vary if more than one HSD shares the same diode/resistor network.

LOAD DUMP PROTECTION

 D_{ld} is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds V_{CC} max DC rating. The same applies if the device will be subject to transients on the V_{CC} line that are greater than the ones shown in the ISO T/R 7637/1 table.

μC I/Os PROTECTION:

If a ground protection network is used and negative transient are present on the V_{CC} line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line to prevent the μC I/Os pins to latch-up.

The value of these resistors is a compromise between the leakage current of μC and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of μC I/Os.

 $-V_{CCpeak}/I_{latchup} \le R_{prot} \le (V_{OH\mu C}-V_{IH}-V_{GND}) / I_{IHmax}$ Calculation example:

For V_{CCpeak}= - 100V and I_{latchup} \geq 20mA; V_{OH μ C} \geq 4.5V 5k Ω \leq R_{prot} \leq 65k Ω .

Recommended R_{prot} value is $10k\Omega$.

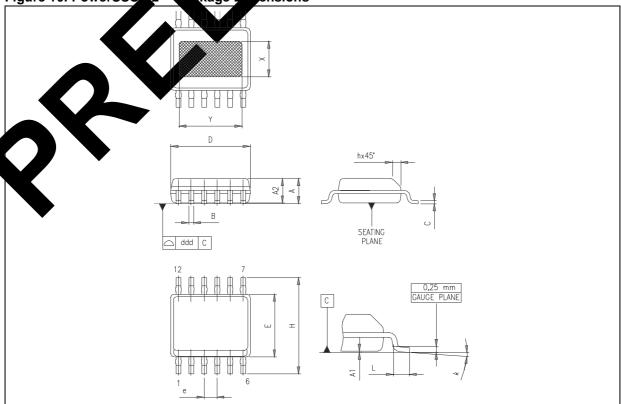
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PACKAGE MECHANICAL

Table 11. PowerSSO-12™ Mechanical Data

Symbol	millimeters			
Symbol	Min	Тур		
DIM.		mm.		
DIWI.	MIN.	TYP	MAX.	
А	1.250		200	
A1	0.000	_	0.100	
A2	1.100		1.650	
В	0.230		0.410	
С	0.190		0.250	
D	4.800		5.000	
E	3.800		4.000	
е		U.ou		
Н	5.800		6.200	
h	0.250		0.500	
L	0.400		1.270	
k			80	
X	1.900	_	2.500	
Υ	V		4.200	
ddd			0.100	

Figure 10. PowerSSO 12™ skage Ditensions



REVISION HISTORY

Table 12. Revision History

Date	Revision	Description of Changes
Oct. 2004	1	First Issue.

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